

AUGER SPECTROSCOPY

MANUFACTURER : JEOL

MODEL : JAMP-30 Auger Microprobe

Equipment unique in Quebec, allowing:

- The in-situ breaking of liquid nitrogen cooled samples for the contamination-free analysis of the broken surface
- Semi-quantitative surface and depth profile analysis of the chemical composition
- Depth profiling up to 1 μm
- Depth and surface mapping available
- Lateral resolution: $\sim 1 \mu\text{m}$
- Equipped with an Argon ion beam for sputtering (depth profiling)

Applications

- Composition profiling of thin films
- Study of surface contamination